

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
2838 2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

RR		Product Description for Ball Grid Probe B1303-C3 from the Web Page of Roku Denzai America, Inc., 4 page
AS		
AT		

EXAMINER

rank Nguya

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE 2/24/00
Filed HerewithGROUP 2829
Unknown

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AK	Product Description for Double Ended PROBES, 51052 SERIES, from the Web Page of Rika Denchi America, Inc., 1 page
AS	Product Description for Test Centers, RM 500 Series Probes, from the Web Page of Rika Denchi America, Inc., 1 page
AT	Product Description for Cost Effective Interconnections for High-40 Products from the Web Page of Rika Denchi America, Inc., 1 page

EXAMINER

mh Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micro Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
UnknownU.S. PTO
09/512968

02/24/00

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA 09/032,184		Alkan et al.			2/27/98
VN	AB 5,495,667	3/5/96	Farnworth et al.	29	843	
	AC					
	AD					
	AE					
	AF					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
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	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AK	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come in Small BGACSP Packages from the Web Page of Johasack International Corporation, 1 page
AT	Product Description for Test Socket Connectors from the Web Page of Johasack International Corporation, 1 page

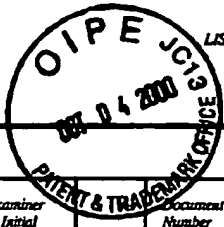
EXAMINER 2

mad Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP
2058829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA 4,560,216	12/24/85	Egawa			
VN	AB 4,754,555	7/5/88	Saltman			
VN	AC 5,475,317	12/12/95	Smith			
	AD					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come in Small Packages from the Web Page of Johnson International Corporation, 1 page
AT	Product Description for Fast Series Cans from the Web Page of Johnson International Corporation, 1 page

EXAMINER

Nah Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000GROUP
Unknown2858
2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA 5,325,052	6/28/94	Yamashita			
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	AC					
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FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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	AN							
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	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

Van Nguyen

DATE CONSIDERED

01/26/2001


*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1 Rev		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M72-1383	SERIAL NO. 09512968	
LIST OF ART CITED BY APPLICANT (See MPEP 609 for details & necessary)				APPLICANT David Membrane		
FILING DATE February 24, 2000				GROUP 2829		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 5,612,574	3/18/97	Summarter et al.			
VN	AB 5,718,333	2/17/98	Hosor et al.			
VN	AC 5,631,333	11/3/98	Maladi et al.			
VN	AD 5,919,548	7/6/99	Barton et al.			
VN	AE 5,551,283	9/3/96	Manassa et al.			
VN	AF 5,492,011	8/23/98	Armano et al.			
	AG					
	AH					
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FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation Yes No
	AK					
	AL					
	AM					
	AO					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
VN	AP	"NTC and PTC Thermistors" http://www.thermopdisc.com/ntc/ppt.htm , 1/7/98, 2 pages.				
VN	AR	"D-5835 Linearized 4-Wire RTD Input" http://www.danalog.com/d5835.htm , 1/7/98, 2 pages.				
VN	AS	"RTD" http://www.instruments.com/rtc.htm , 1/7/98, 3 pages.				
VN	AT	"Low Cost Thermal-Rubber (TM) uses thin film RTD" http://www.mmc.com/17824w.htm , 1/7/98, 1 page.				
VN	AU	"Silicon Processing for the VLSI Era" Volume 1 - Process Technology, Second Edition, S. Wolf et al., 2000, pps 23-25 and pps. 641-645. (month unavailable)				
EXAMINER <i>anh Nguyen</i>			DATE CONSIDERED 01/22/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 1622-1353	SERIAL NO. 09512 953
LIST OF ART CITED BY APPLICANT (On several sheets if necessary)				APPLICANT Microsoft Technology, Inc.	
				FILING DATE February 24, 2000	PRIORITY GROUP 2829
U.S. PATENT DOCUMENTS					
Examiner Initial	Class	Serial Number	Date	Name	Class
VN	AA	3,710,251	1/9/1973	Hegge et al.	
	AB				
	AC				
	AD				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)					
	AE				
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	AL				
EXAMINER <i>rich Nguyen</i>			DATE CONSIDERED 01/22/04		
*EXAMINER: Indicate reference considered, whether or not citation is in conformance with MPEP §409. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication if applicable.					

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 1622-1763		SERIAL NO. 09512 959	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Machon Technology, Inc.		FILING DATE February 24, 2000	
				PRIORITY GROUP 255		2829	
U.S. PATENT DOCUMENTS							
Citation Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA	4,912,600	3/1990	Jaeger et al.	361	70C	
VN	AB	5,436,494	7/1995	Moskals	257	45	
VN	AC	5,963,639	10/1999	Leuf et al.	340	6-17	
	AD						
OTHER REFERENCES (including Author, Title, Date, Patent Pages, Etc.)							
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EXAMINER <i>anh Nguyen</i>				DATE CONSIDERED <i>01/22/04</i>			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M77-1353		SERIAL NO. 05/512 658	
				APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2553 7829	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Class	Subclass	Date	Name	Class	Subclass	Filing Date if Appropriate
W	AA	4355 463	10/25/1982	Burns			
	AB						
	AC						
	AD						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>mh Nguy</i>				DATE CONSIDERED <i>01/22/04</i>			
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000PRIORITY GROUP
2858-2829

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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
	AC					
	AD					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99; Original Application filed 2/27/98; Pending Claims.
VN	AF	Advertisement for Probe Technology: www.idirect.com ; Interconnect Devices, Inc.; 1 page; 3/6/98
VN	AG	Good Things Come In Small BGA/CSP Packages: www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98
VN	AH	Product Description for Double Ended Probes, B1052 Series: www.testprobe.com/products/b1052.html ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AI	Product Description for Test Cerners, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products: www.testprobe.com/products/io.htm#b1303 ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AK	Product Description for Ball Grid Probe B1303-C3: www.testprobe.com/products/io.htm#b1303 ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AL	Product Description for Test Socket Contacts: www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98

EXAMINER

mark Nguyen

DATE CONSIDERED

10/25/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
David R. HembreeFILING DATE
February 24, 2000GROUP
2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 3,440,407	4/22/69	Golstos et al.			
	AB 3,614,345	10/18/71	Quinn			
	AC 3,663,306	8/8/72	Bulthuis et al.			
	AD 4,332,081	6/1/82	Francis			
	AE 4,518,944	5/21/85	Faris			
	AF 4,703,556	11/3/87	Hubner			
	AG 5,141,334	8/25/92	Castles			
	AH 5,347,869	9/20/94	Shio et al.			
	AI 5,406,109	4/11/95	Whitney			
	AJ 5,436,646	7/25/95	McArthur et al.			
V	AK 5,446,437	8/29/95	Bantien et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
VN	AL 2338778	7/1977	France				
	AM 56-12521	2/1961	Kobayashi, Japan				
	AN 2-268482	11/1990	Yamanishi, Japan				
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AR	"Application Guide Temperature Sensors", Watlow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993.
VN	AS	"In-Situ survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum", Lechevallier, LeHuerou, Richon, Sarrau, & Gousault, J. Phys. III France, Vol. 5, pp. 403-418, 04/95 (Abstract only).
VN	AT	"Temperature Metrology for CD Control in DUV Lithography", Jeffrey Parker and Wayne Renken, pp. 111-112, 114, 116, 09/17/97.

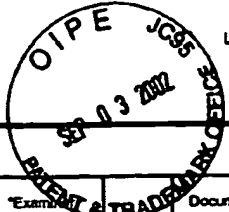
EXAMINER


mark Nguyen

DATE CONSIDERED

03/24/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1383	SERIAL NO. 09512,968	
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				FILING DATE February 24, 2000		PRIORITY GROUP 2658 2829
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 6,004,471	12/21/1999	Chuang			
VN	AB 5,550,526	8/27/1996	Mottahed			
	AC					
	AD					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)						
VN	AE	P. Van Zant, "Microchip Fabrication," (4th ed. 2000); pps 567-569.				
	AF					
	AG					
	AH					
	AI					
	AJ	EV1826641887				
	AK					
	AL					
EXAMINER <i>Mark Nguyen</i>			DATE CONSIDERED 12/09/02			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

Form 870		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1353		SERIAL NO. 08512,955	
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2858-7829	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA 5,503,034	4/2/1996	Arbino et al.				
VN	AB 5,984,395	2/1/2000	Glovatsky et al.			RECEIVED	
VN	AC 5,645,784	7/1/97	Angelopoulos et al.			JUN 20 2004	
VN	AD 5,437,189	8/1/95	Brown et al.				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
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EXAMINER <i>mark Ngump</i>			DATE CONSIDERED 09/03/04				
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		<div style="border: 1px solid black; border-radius: 50%; padding: 5px; display: inline-block;"> JAN 28 2002 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE </div>		ATTY. DOCKET NO. M22-1363		SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use separate sheets if necessary)				APPLICANT David Hembree		FILING DATE February 24, 2000	
				GROUP 2829			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA	5,612,574	3/18/97	Summerfelt et al.			/
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Mañadi et al.			
	AD	5,919,548	7/8/99	Barton et al.			
	AE	5,551,283	9/3/98	Manaka et al.			
	AF	5,492,011	2/20/98	Amano et al.			
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FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
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AK							
AL							
AM							
AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
VN	AP		"NTC and PTC Thermistors"; http://www.thermodisc.com/ntcptc.html ; 1/7/98; 2 pages.
VN	AR		"DI-5B35 Linearized 4-Wire RTD Input"; http://www.dataq.com/di5b35.html ; 1/7/98; 2 pages.
VN	AS		"RTD"; http://www.rti-sensors.com/rtds.html ; 1/7/98; 3 pages.
VN	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; http://www.minco.com/s17624nr.html ; 1/7/98; 1 page.
VN	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology; Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845. (month unavailable)

EXAMINER <i>Nguyen</i>	DATE CONSIDERED 05/30/2002
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